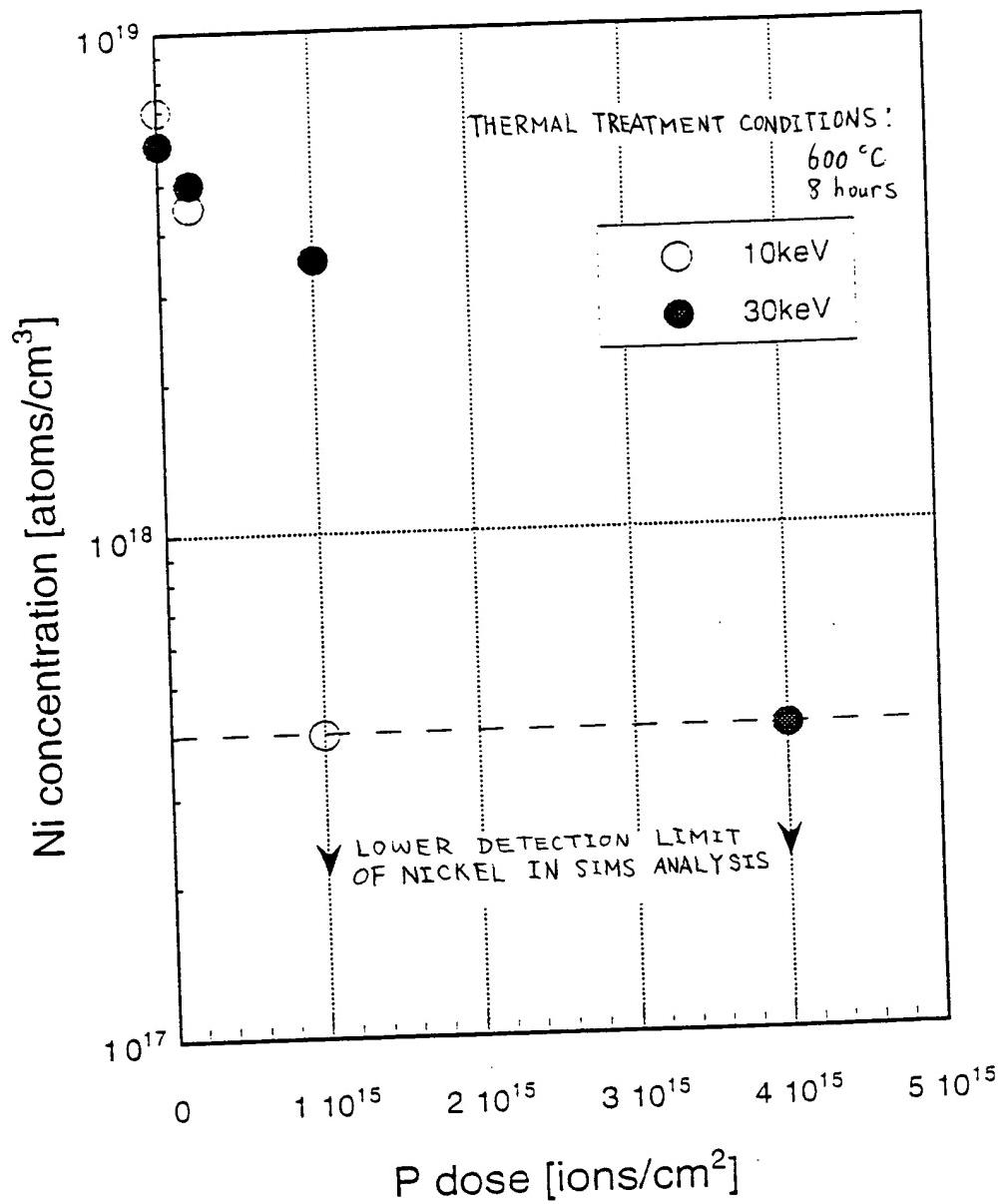


Fig. 1



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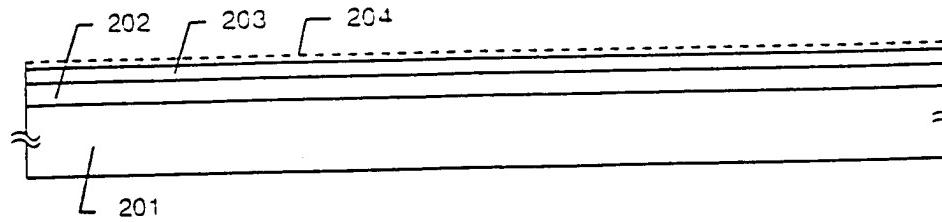


Fig. 2A

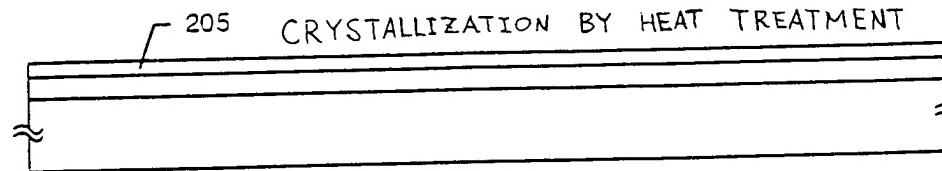


Fig. 2B

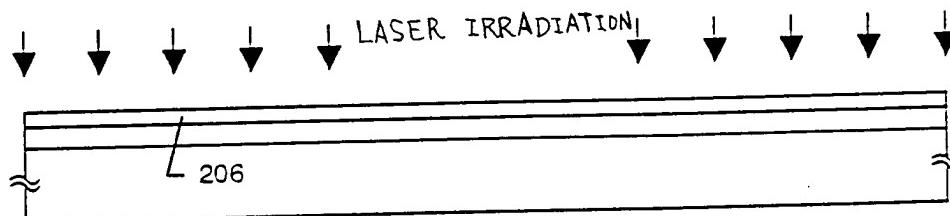


Fig. 2C

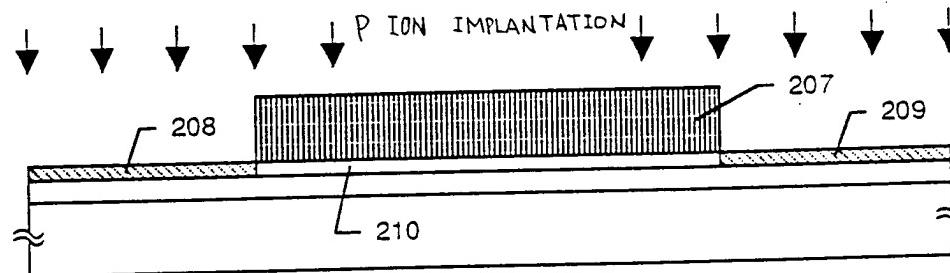


Fig. 2D

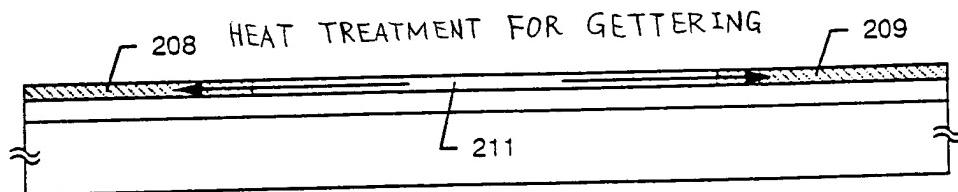


Fig. 2E

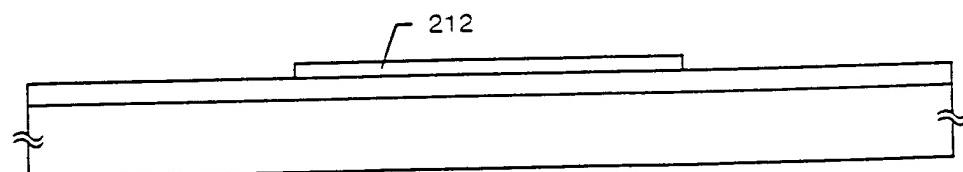


Fig. 2F

Fig. 3A

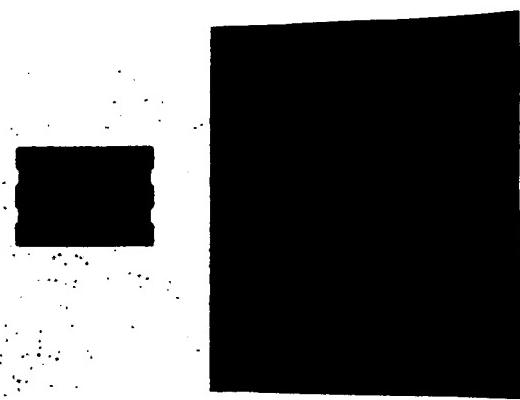


Fig. 3D



Fig. 3B

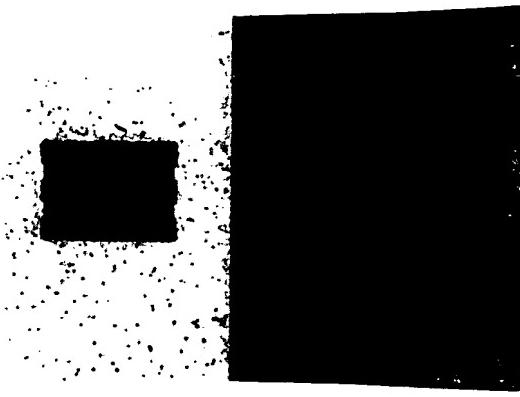


Fig. 3E

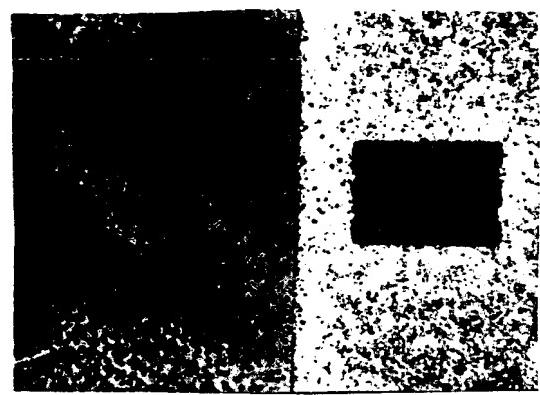
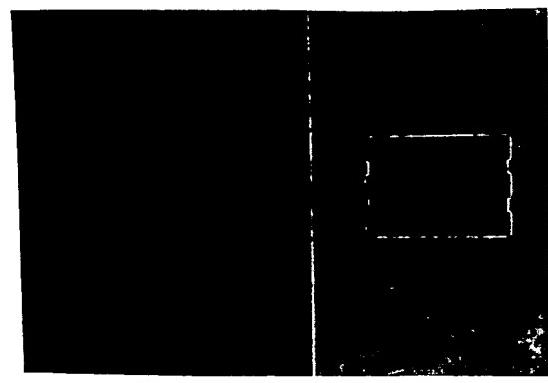


Fig. 3C



Fig. 3F



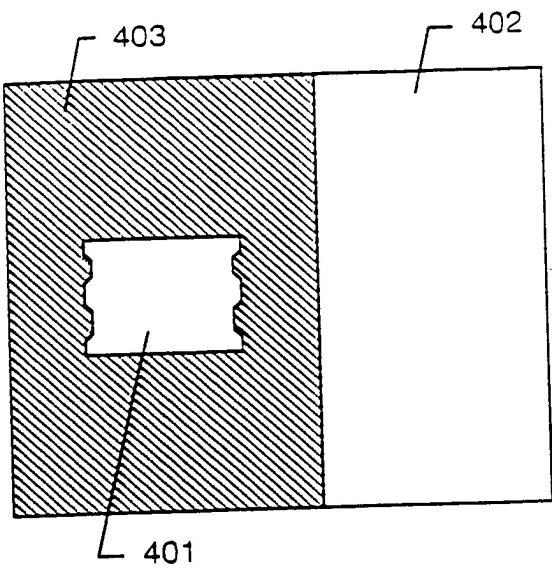


Fig. 4

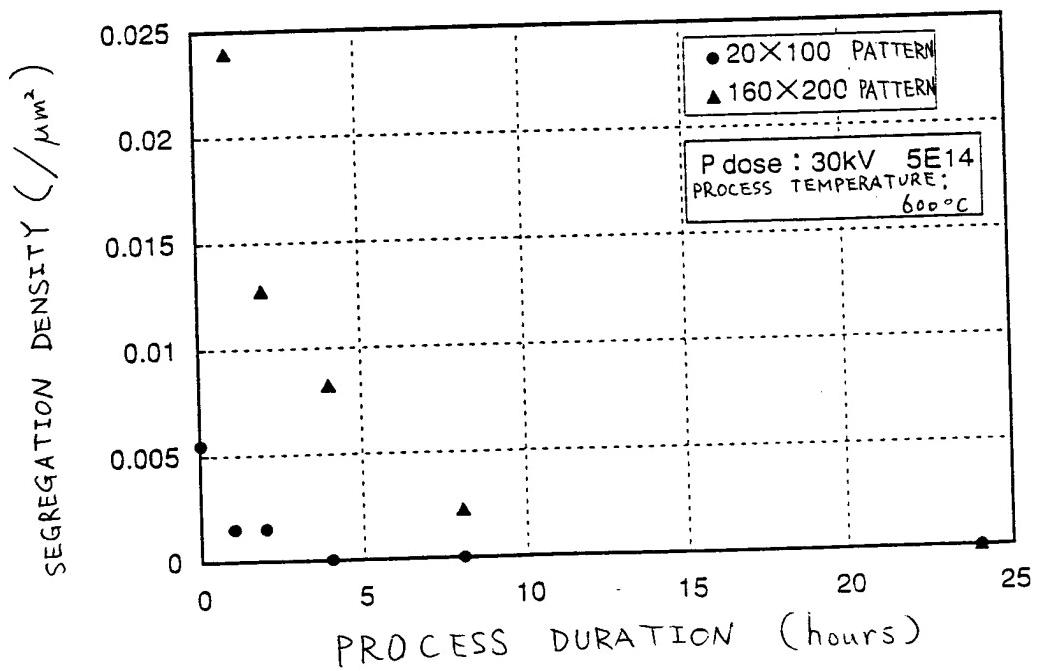


Fig. 5

Fig. 6A

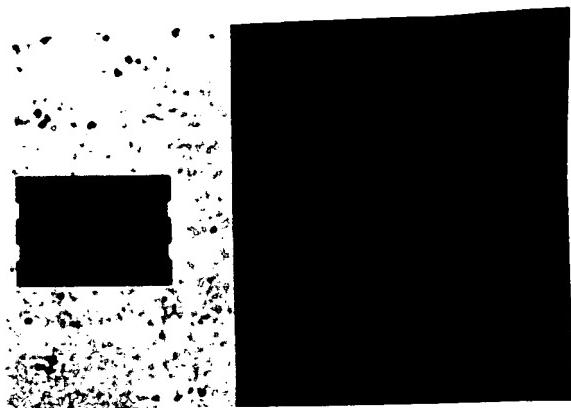


Fig. 6D

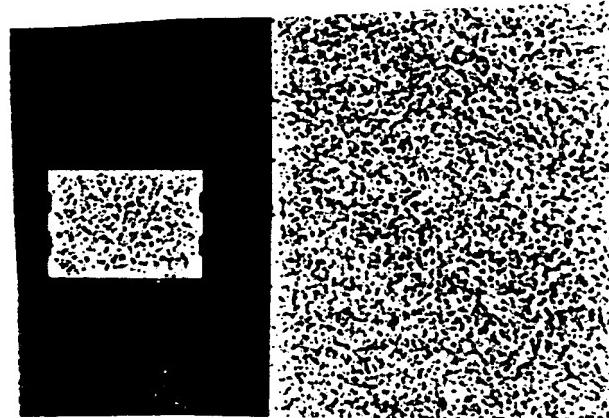


Fig. 6B

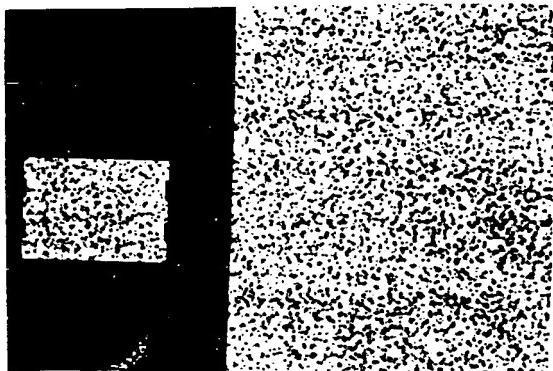


Fig. 6E

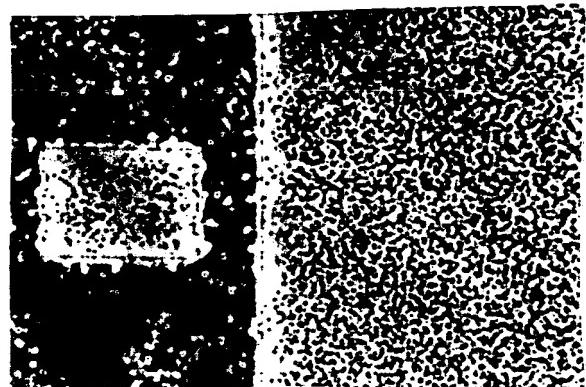


Fig. 6C

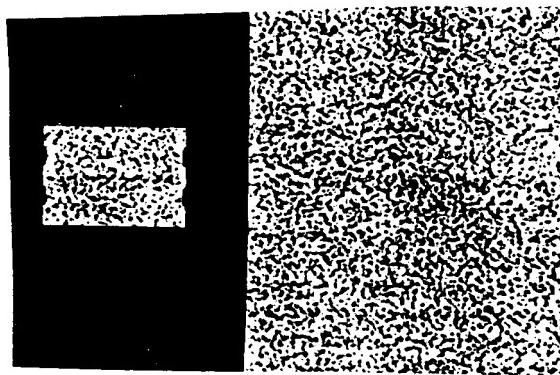


Fig. 6F



Fig. 7

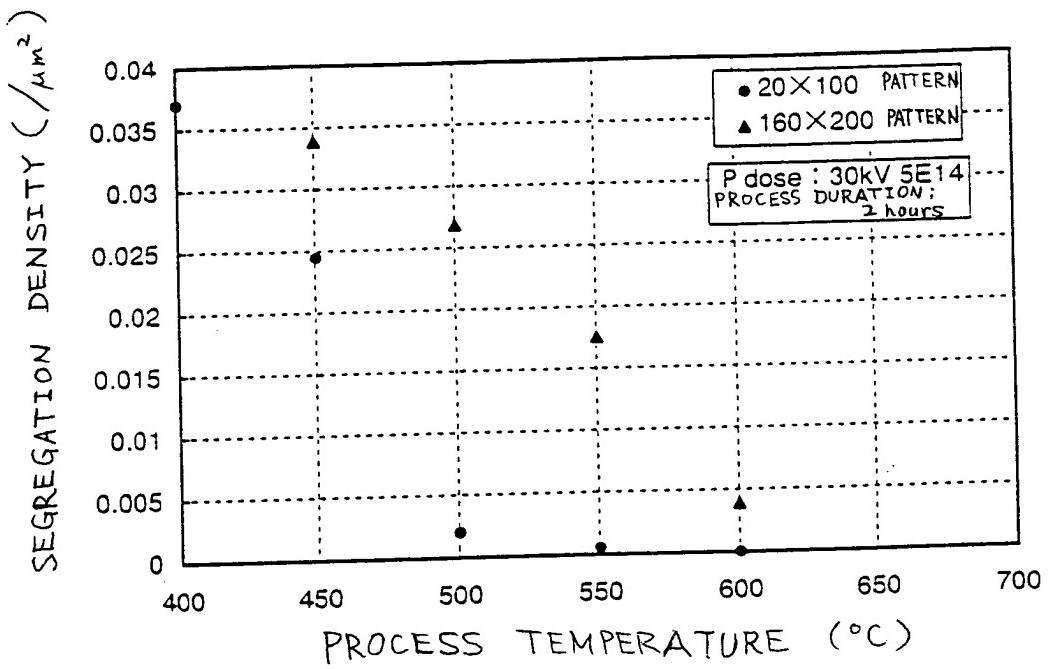


Fig. 8A

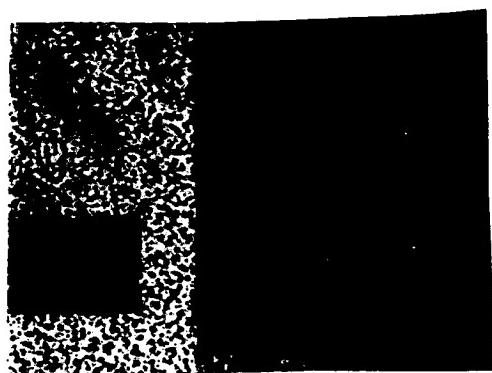


Fig. 8D

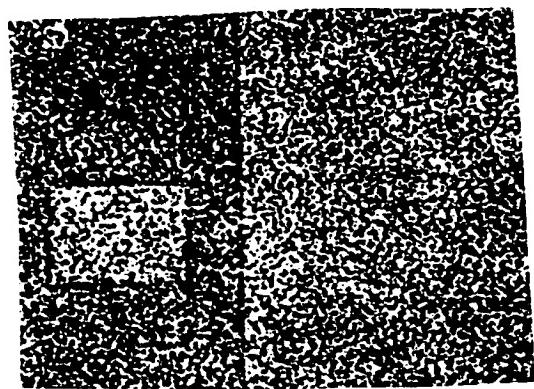


Fig. 8B

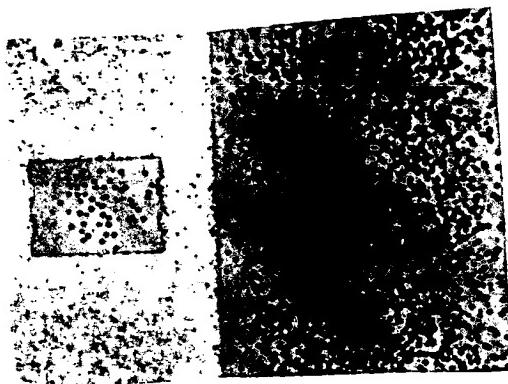


Fig. 8E



Fig. 8C

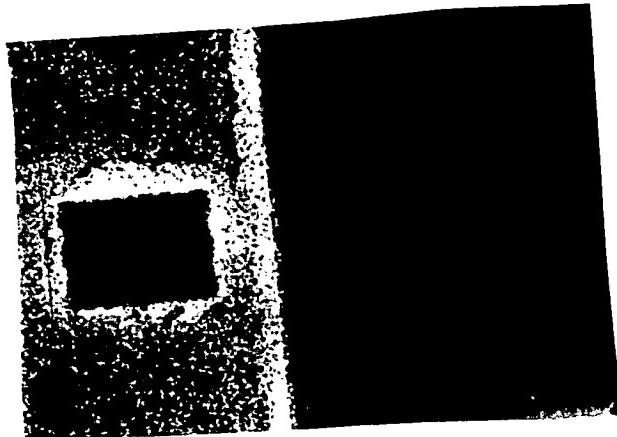
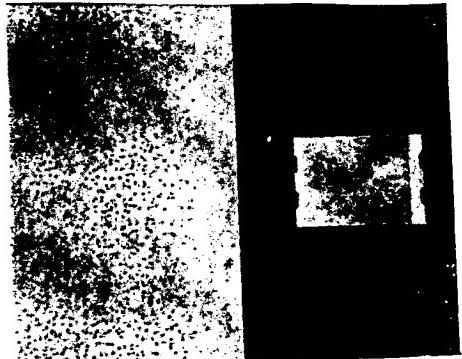


Fig. 8F



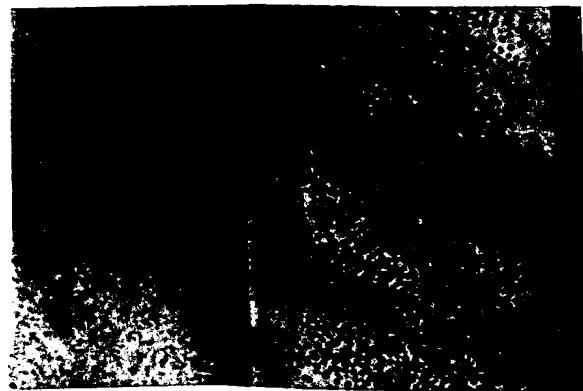
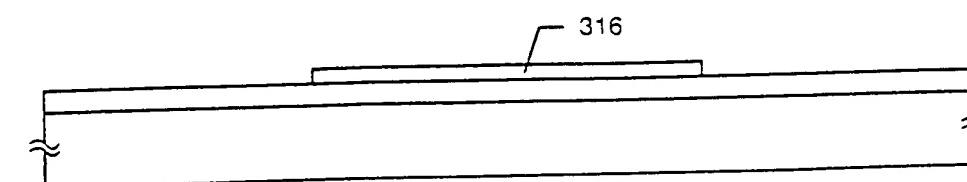
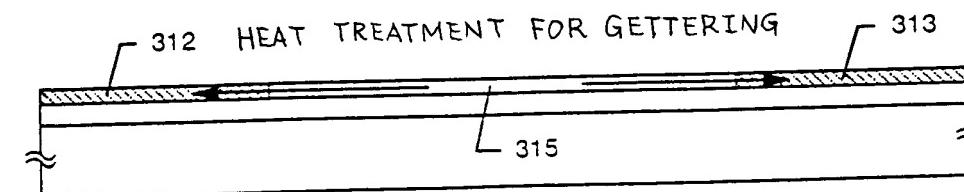
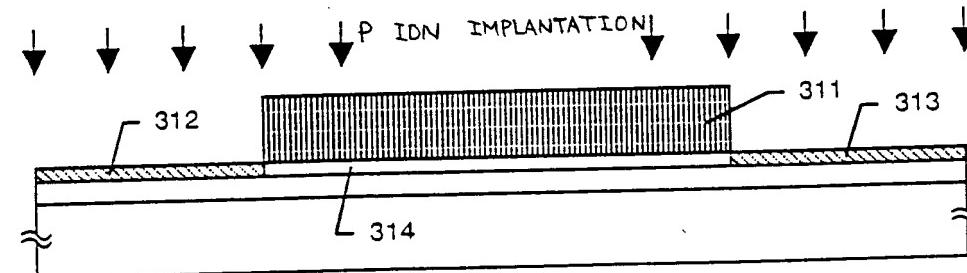
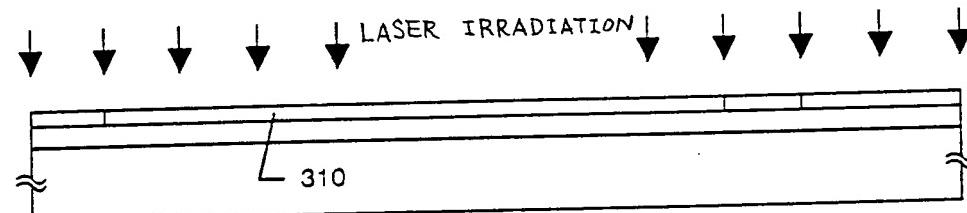
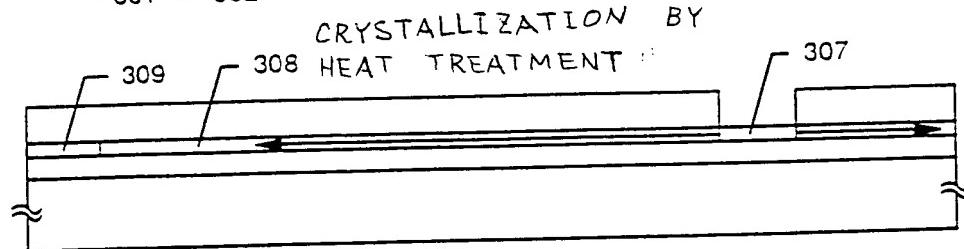
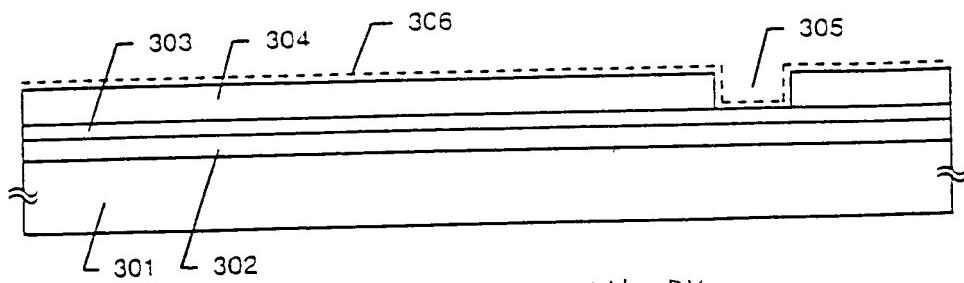


Fig. 9A



Fig. 9B



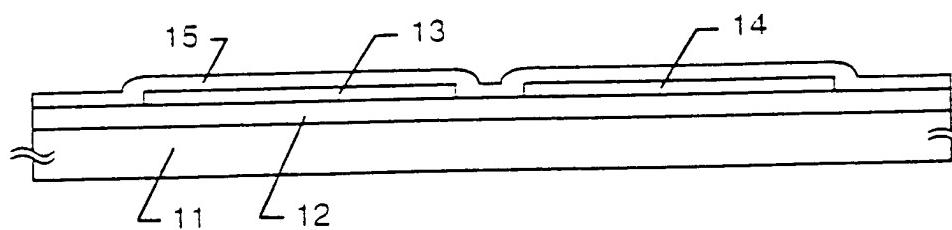


Fig. 11A

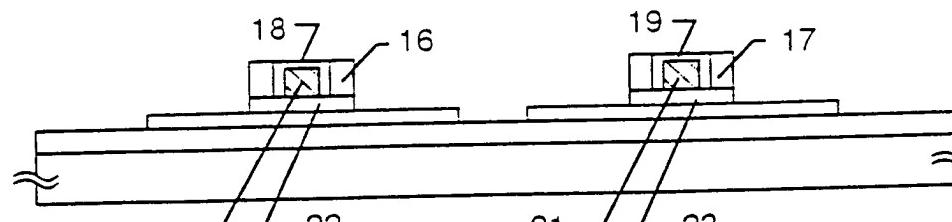


Fig. 11B

ADDITION OF IMPURITY IONS WHICH IMPART N-TYPE CONDUCTIVITY  
(FORMATION OF  $n^-$  REGION/ $n^+$  REGION)

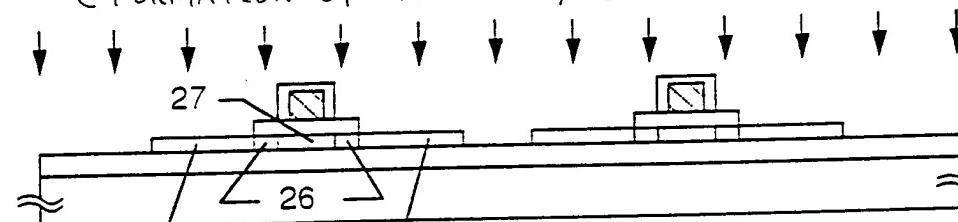


Fig. 11C

ADDITION OF IMPURITY IONS FOR IMPARTING P-TYPE CONDUCTIVITY  
(FORMATION OF  $p^-$  REGION/ $p^+$  REGION)

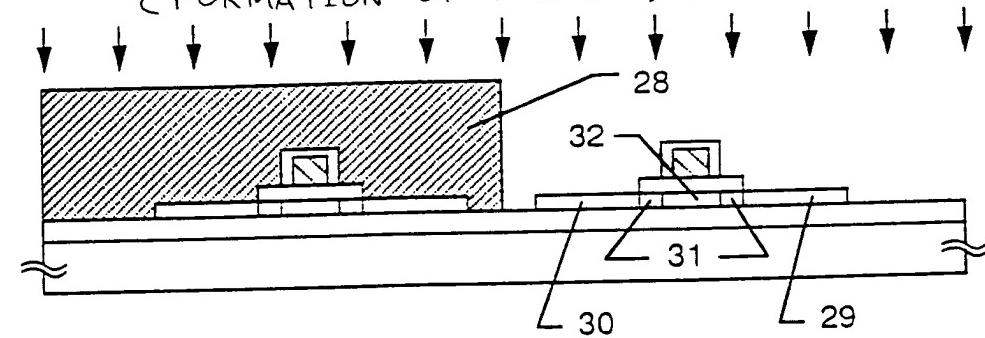


Fig. 11D

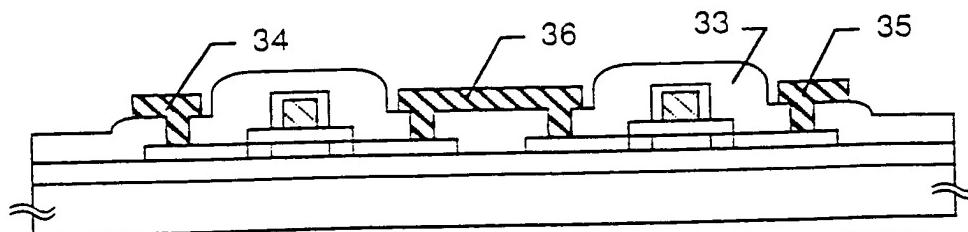


Fig. 11E

N-CHANNEL TYPE TFT      P-CHANNEL TYPE TFT

N-CHANNEL TYPE TFT SUBJECTED TO  
GETTERING TREATMENT

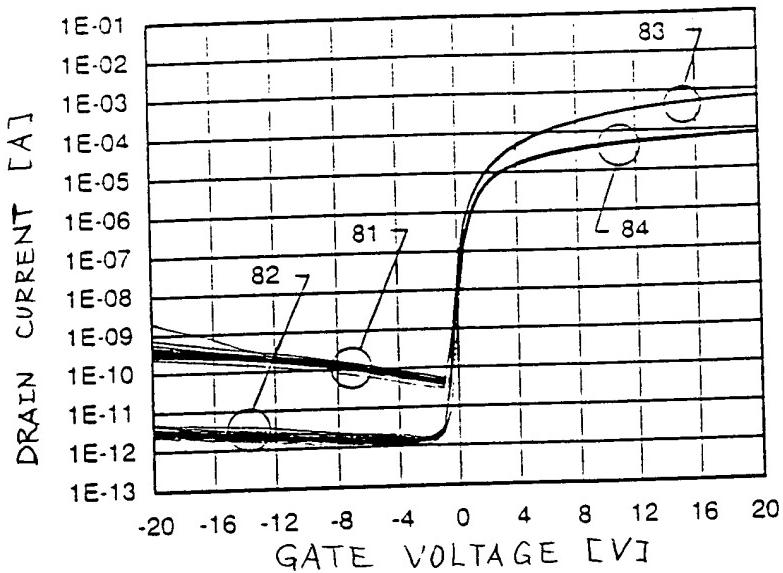


Fig. 12 A

N-CHANNEL TYPE TFT WITHOUT APPLYING  
GETTERING TREATMENT

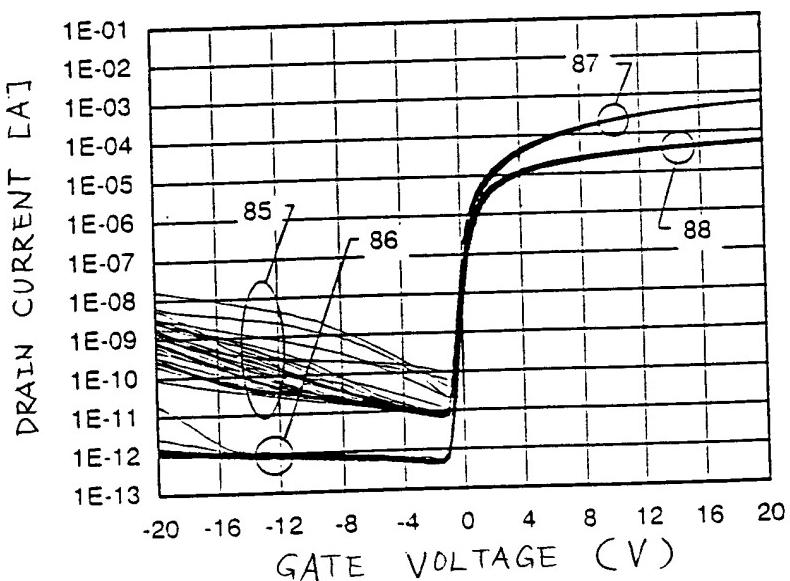


Fig. 12 B

2000-2005060

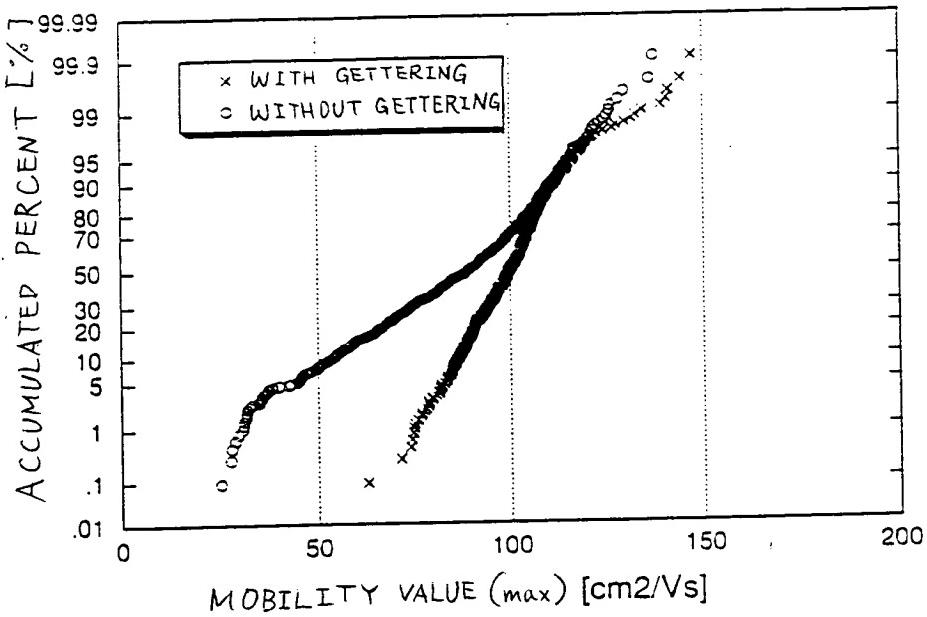


Fig. 13 A

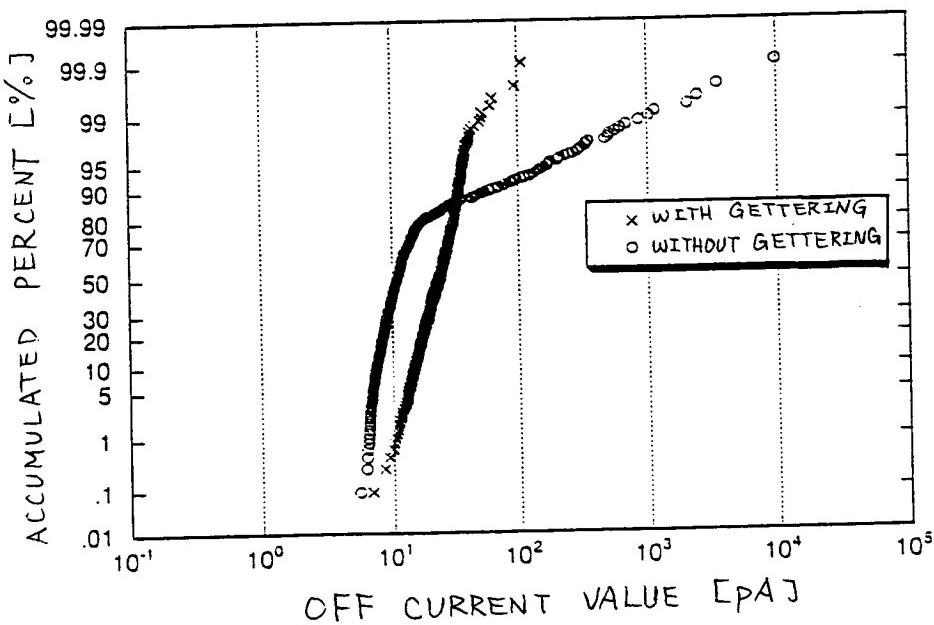
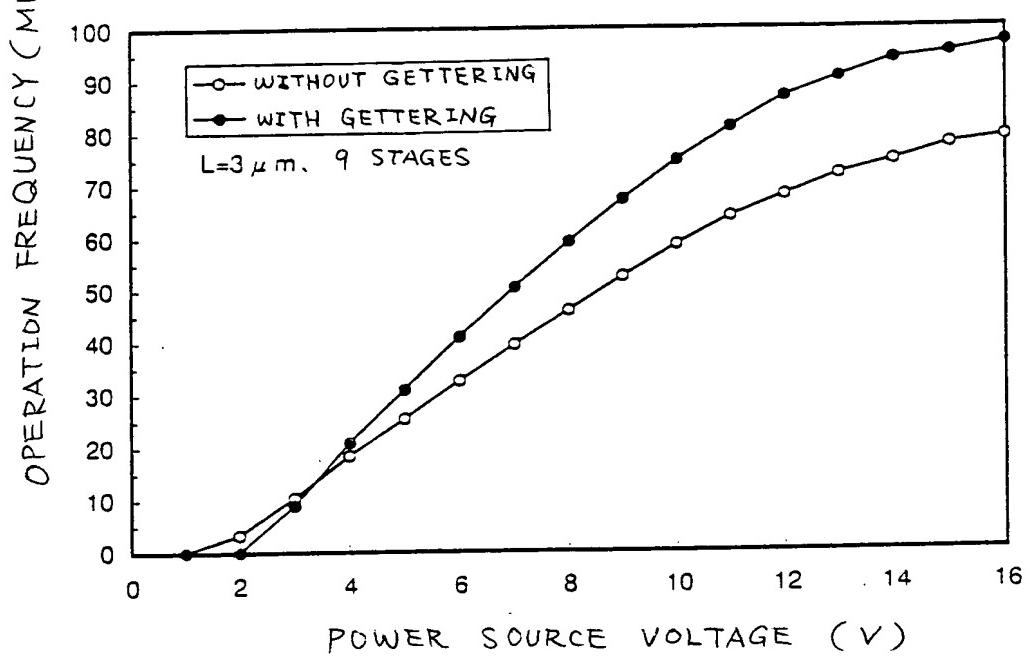


Fig. 13 B

Fig. 14



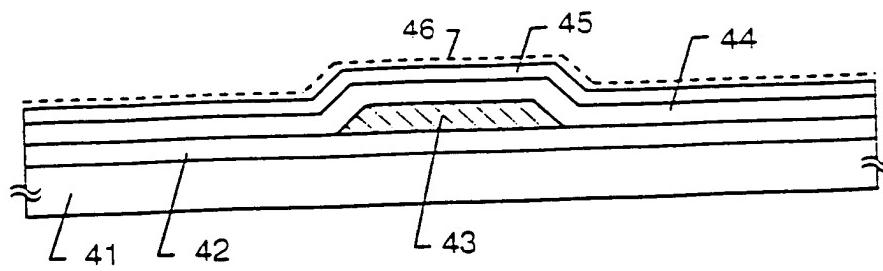


Fig. 15A

HEAT TREATMENT FOR CRYSTALLIZATION

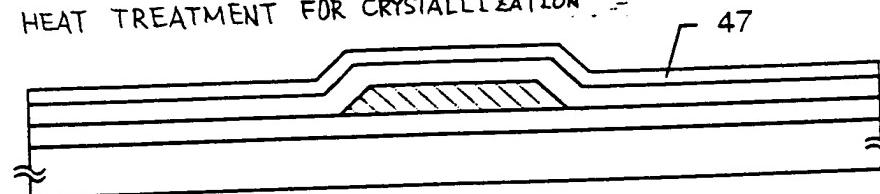


Fig. 15B

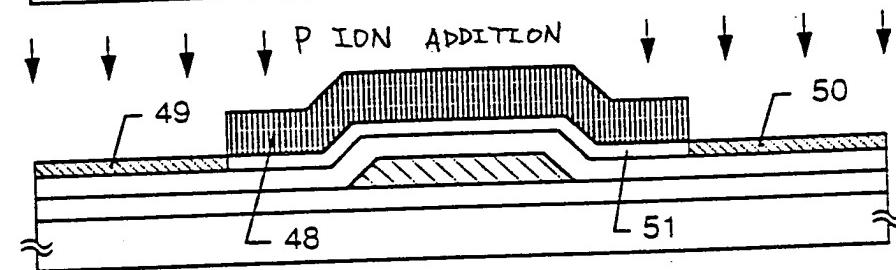


Fig. 15C

HEAT TREATMENT FOR GETTERING

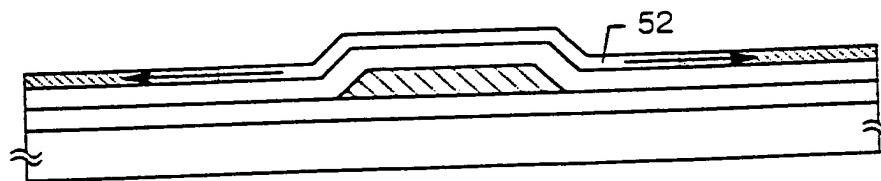


Fig. 15D

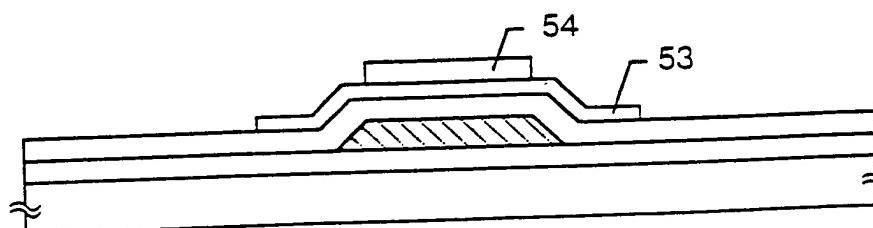


Fig. 15E

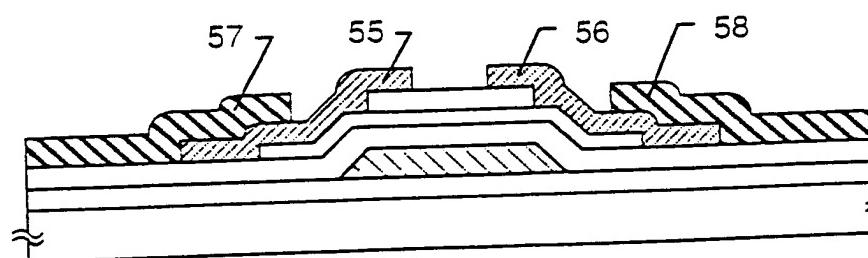


Fig. 15F

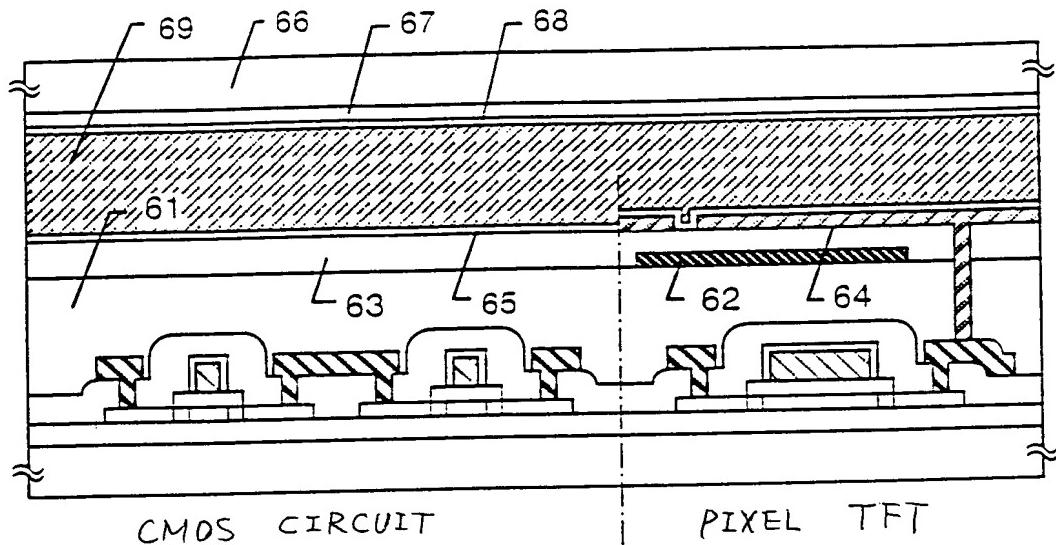


Fig.16

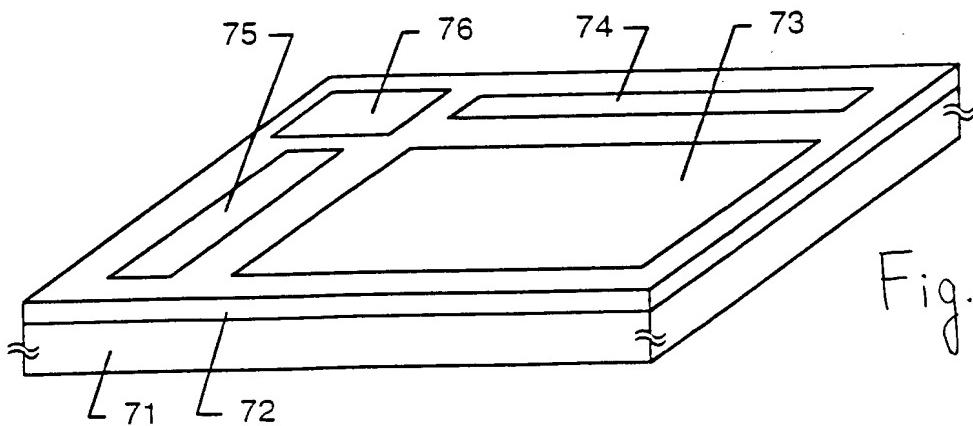


Fig.17

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